

**MACOM**

100 Chelmsford Street  
Lowell, MA 01851  
+1 978.656.2500

www.macom.com



2 June 2022

PCN-01542

Subject: Additional testing and packaging site.

Digi-Key Corporation  
701 Brooks Ave South  
Thief River Falls, Minnesota 56701

Dear Valued Customer,

MACOM Technology Solutions has a goal of providing redundant manufacturing capability for increased surge capacity as well as an uninterrupted supply chain. In alignment with this goal, we are pleased to announce an additional testing and packaging site for the parts listed in the next pages.

In addition to our current testing and packaging sites, we planned to test and package these parts at our long-standing Contract Manufacturer, Year 2000, Ho Chi Minh City, Vietnam. Year 2000 is a valued, high-quality manufacturing partner for many MACOM products.

In accordance with MACOM Technology Solutions' customer notification policy, you are receiving this notice because you have purchased one or more of the products listed in the previous two-year period.

Please contact your local sales representative if you have any specific questions.

Sincerely

Tom Galluccio  
Director, Product Marketing  
[thomas.galluccio@macom.com](mailto:thomas.galluccio@macom.com)

**Appendix I**  
Affected part numbers

Part Number	Part type
913R7K-BOO	Capacitor
9110RM	Capacitor
9010R0K-SP	Capacitor
9030RM-15	Capacitor
M2X8300	Capacitor
MPN7420-C12	Diode
MX40051-11	Diode
M5X6093	Diode
MMP7065-11	Diode

**Appendix II**  
The new testing and assembly facility



**Appendix III**  
Qualification process capability data

Two representative part numbers(MX51267-11 and MC2S022025-025) are tested and qualified in Year 2000 as below, and the rest parts in the pcn can be qualified by similarity to the representative parts as they have the same production process.

**1. Diode.**

**MX51267-11**

Test conditions: IR1max=10uA, under -1100V.

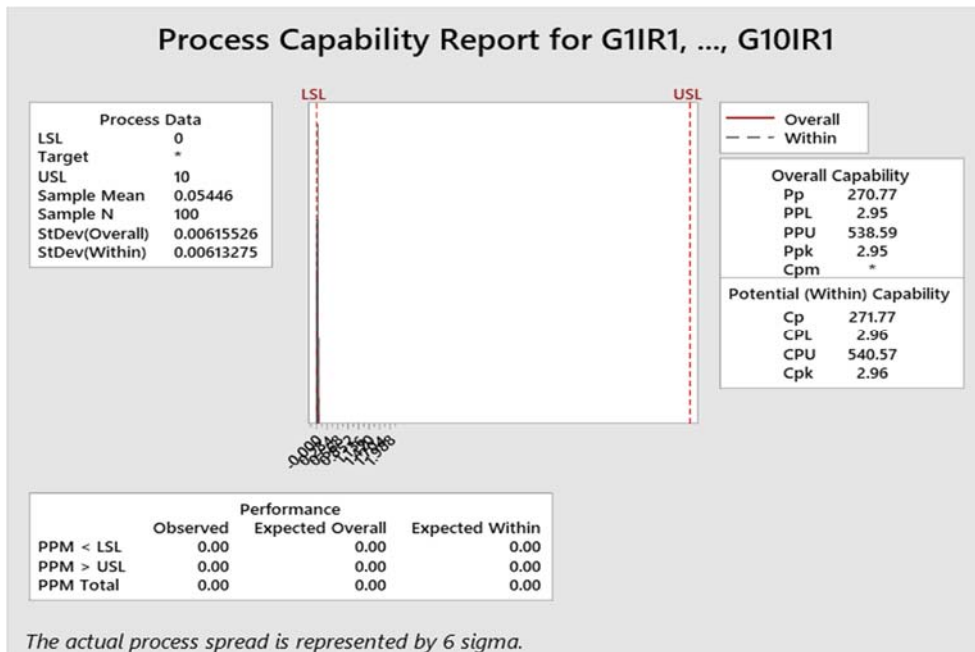
IR2max=0.05uA, under -1000V.

Cj1max=0.25pF, under -28V.

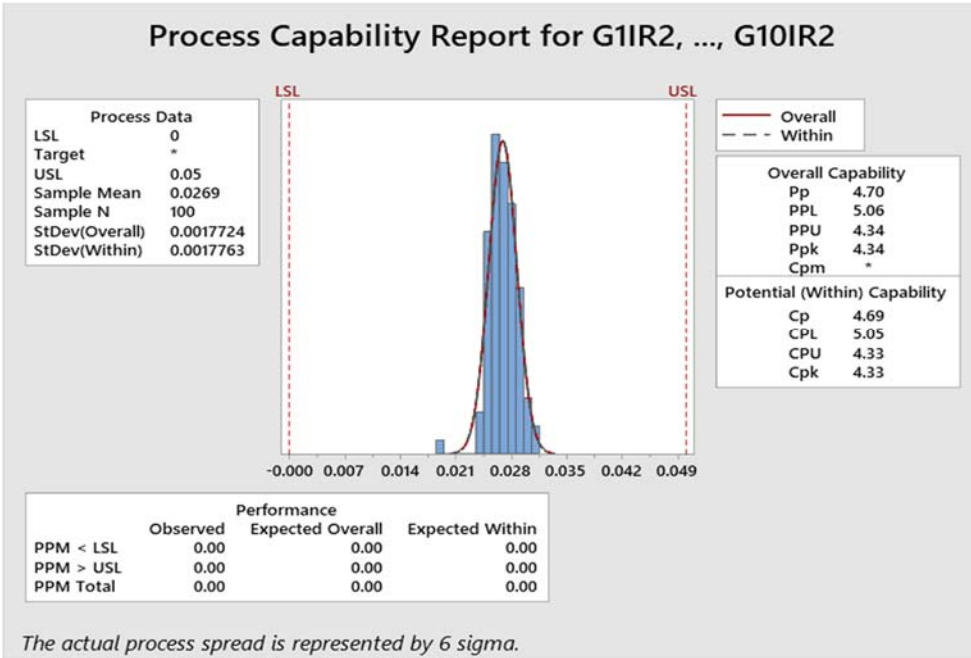
VF1max=1.25V, under 100mA.

Sample size=100,10 sub-groups.

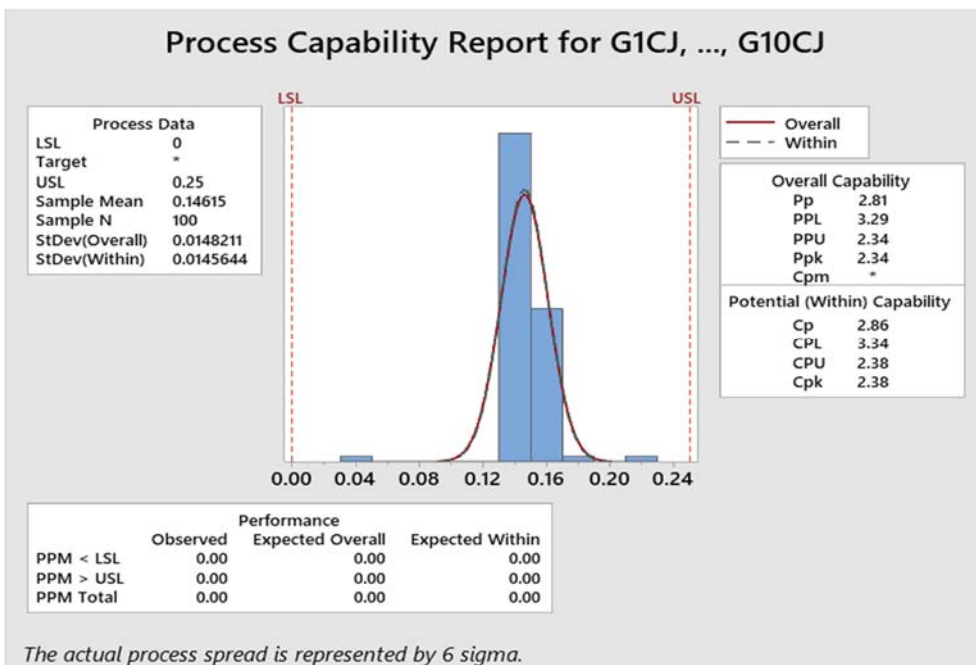
**IR1:**



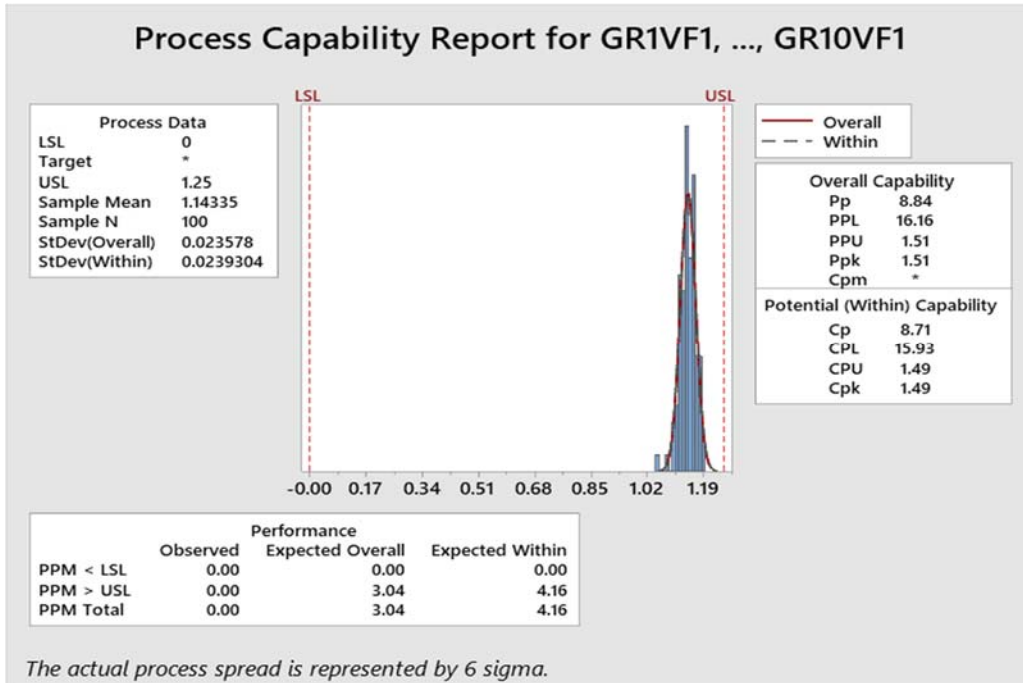
**IR2:**



**Cj1:**



**VF1:**



**2. Capacitor.**

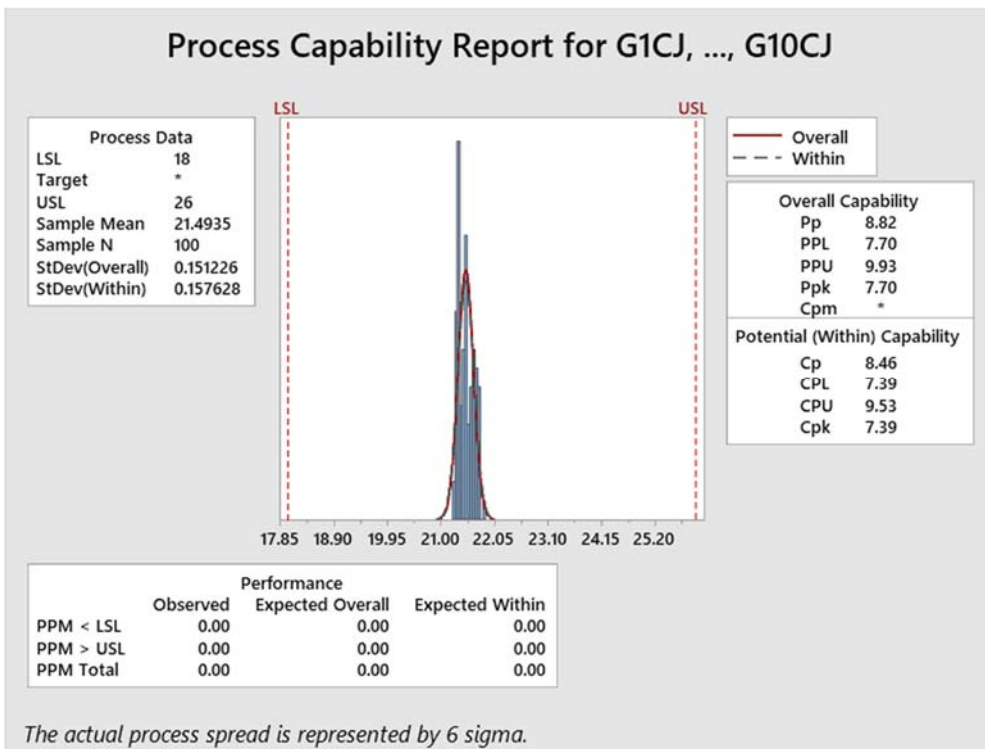
**MC2S022025-025**

Test conditions: Cj1min=18pF, Cj1max=26pF, under 0V.

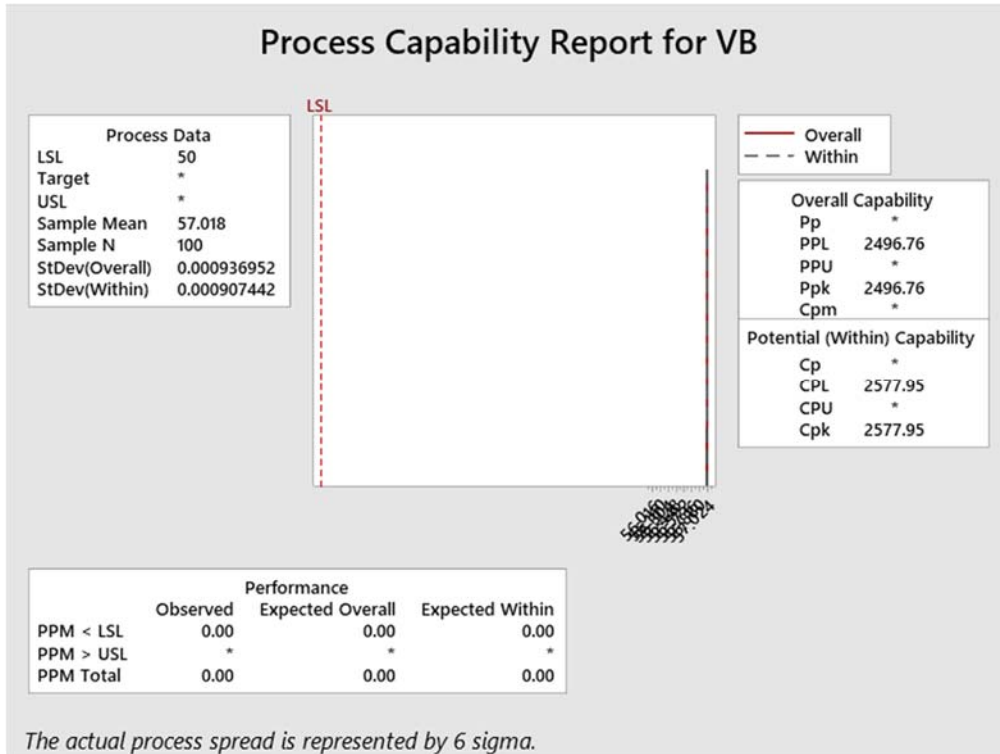
VBmin=50V, under -10uA.

Sample size=100,10 sub-groups.

**CJ1:**



**VB:**





**Appendix IV**  
Qualification Gage R&R testing data

**1. Diode test parameters**

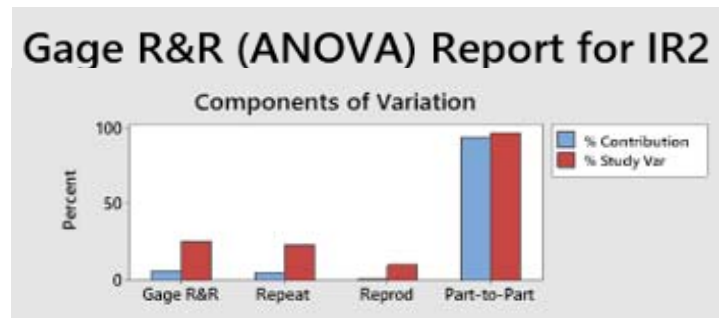
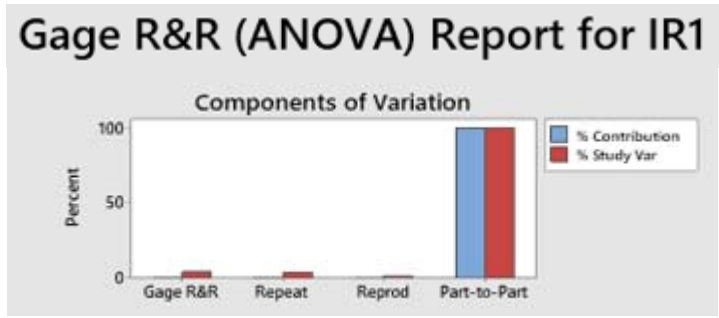
GR&R summary:

Specification:-

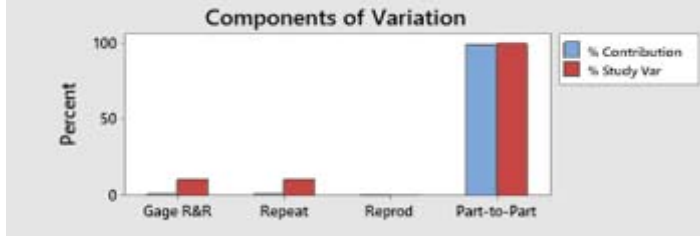
a) GR&R Contribution %  $\leq$ 10%

b) GR&R Variation %  $\leq$ 30%

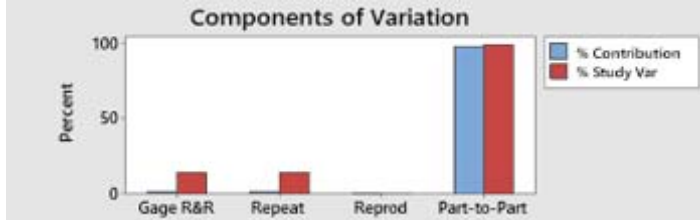
Parameter	GR&R Contribution %	GR&R Variation %	Result
IR1	0.21	4.57	PASS
IR2	6.62	25.72	PASS
Cj1	1.13	10.65	PASS
VF1	2.13	14.6	PASS



### Gage R&R (ANOVA) Report for Cj1



### Gage R&R (ANOVA) Report for VF1



## 2. Capacitor test parameters

GR&R summary:

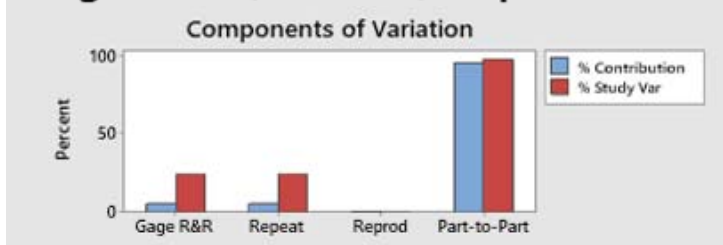
Specification:-

a) GR&R Contribution %  $\leq 10\%$

b) GR&R Variation %  $\leq 30\%$

Parameter	GR&R Contribution % GR&R	GR&R Variation% GR&R	Result
VB	5.69	23.85	PASS
Cj1	0	0.67	PASS

### Gage R&R (ANOVA) Report for Vb



## Gage R&R (ANOVA) Report for Cj1

